

Claims

1. Silyl alkyl ester having the formula (I)

$$\begin{array}{c|c}
C & C & C \\
C & C \\$$

(I)

wherein

 R_1 , R_2 , and R_3 are equal or different and represent alkyl, aryl and heteroaryl,

 R_4 and R_5 are equal or different and represent hydrogen, halogen, alkyl, aryl and heteroaryl,

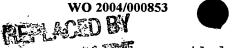
n is an integer from 1 to 10,

R₆ is a substituent selected from halogen, alkyl, aryl, heteroaryl, hydroxy, alkoxy, arylether, substituted and unsubstituted amino group, carboxy group, carboxylic acid ester group, carboxylic acid amide group, sulfonic acid group, sulfonic acid ester group, sulfonyl, thio, thioether and nitro,

m is an integer from 0 to 4,

T, X, Y and Z each represent carbon,

a benzo group, which is substituted m-fold with R_6 or which is unsubstituted, is condensed on one of the bonds T-X, X-Y or Y-Z to form a trinuclear aromatic ring system, wherein the silyl alkyl ester group is substituted at the middle ring of said trinuclear aromatic ring system,



excluded, in which

 R_1 , R_2 , and R_3 each represent ethyl, R_4 and R_5 each represent hydrogen,

n = 1,

m = 0

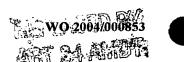
an unsubstituted benzo group is condensed on the X-Y bond and the silyl ester group is substituted on the 9-carbon atom of the trinuclear aromatic ring system.

- 2. Silyl alkyl ester according to Claim 1, wherein R_1 , R_2 , and R_3 each represent alkyl.
- 3. Silyl alkyl ester according to Claim 1 or 2, wherein R_1 , R_2 , and R_3 are selected, independently of one another, from methyl, ethyl, n-propyl, iso-propyl, n-butyl, 2-methylpropyl, 1-methylpropyl and 1,1-dimethylethyl.
- 4. Silyl alkyl ester according to any one of Claims 1 to 3, wherein R_1 , R_2 , and R_3 each represent methyl or ethyl.
- 5. Silyl alkyl ester according to any one of Claims 1 to 4, wherein R_4 and R_5 each represent hydrogen.
- 6. Silyl alkyl ester according to any one of Claims 1 to 5, wherein n is an integer from 1 to 5, particularly from 1 to 3, yet more preferably 1 or 3 and most preferably 3.
- 7. Silyl alkyl ester according to any one of Claims 1 to 6, wherein a benzo group, which is m-fold substituted with R₆ or which is unsubstituted, is condensed on the X-Y bond.
- 8. Silyl alkyl ester according to Claim 7, wherein an unsubstituted benzo group is condensed on the X-Y bond and m=0.
- 9. Silyl alkyl ester according to any one of Claims 1 to 6, wherein a benzo group, which is m-fold substituted with R_6

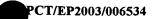


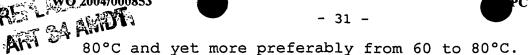
or Y-Z bond.

- 10. Silyl alkyl ester according to Claim 9, wherein an unsubstituted benzo group is condensed on either the T-X or Y-Z bond and m=0.
- 11. Composition which comprises at least one silyl alkyl ester according to any one of Claims 1 to 10 and at least one further reactive silane.
- 12. Composition according to Claim 11, wherein the reactive silane is selected from alkoxysilanes and halogen silanes, particularly chlorosilanes.
- 13. Composition according to Claim 11 or 12, wherein the reactive silane is selected from triethoxysilane (HTEOS), tetraethoxysilane (TEOS), methyltriethoxysilane (MTEOS), dimethyldiethoxysilane, tetramethoxysilane (TMOS), methyltrimethoxysilane (MTMOS), trimethoxysilane, dimethyldimethoxysilane, phenyltriethoxysilane phenyltrimethoxysilane (PTMOS), diphenyldiethoxysilane, diphenyldimethoxysilane, trichlorosilane, methyltrichlorosilane, ethyltrichlorosilane, phenyltrichlorosilane, tetrachlorosilane, dichlorosilane, methyldichlorosilane, dimethyldichlorosilane, chlorotriethoxysilane, chlorotrimethoxysilane, chloromethyltriethoxysilane, chloroethyltriethoxysilane, chlorophenyltriethoxysilane, methyltrimethoxysilane, chloroethyltrimethoxysilane and chlorophenyltrimethoxysilane.
- 14. Composition according to any one of Claims 11 to 13, wherein the reactive silane is selected from triethoxysilane (HTEOS), tetraethoxysilane (TEOS), methyltriethoxysilane (MTEOS), tetramethoxysilane (TMOS), methyltrimethoxysilane (MTMOS), phenyltriethoxysilane (PEOS) and phenyltrimethoxysilane (PTMOS).



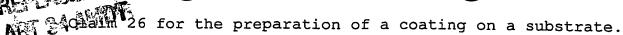
- 15. Composition according to any one of Claims 11 to 14, which comprises a solvent or solvent mixture.
- 16. Composition according to Claim 15, wherein the solvent or solvent mixture comprises at least one component selected from water, linear or branched alkyl alcohol having 1 to 6 carbon atoms, linear or branched ketone having 1 to 6 carbon atoms, linear or branched carboxylic acid ester having 1 to 6 carbon atoms and linear or branched carboxylic acid amide having 1 to 6 carbon atoms.
- 17. Composition according to Claim 15 or 16, wherein the solvent or solvent mixture comprises at least one component selected from water, acetone, 1-propanol, 2-propanol, butanol, methylisobutylketone, methoxypropanol, propoxypropanol, ethyl acetate and propyl acetate.
- 18. Composition according to any one of Claims 11 to 17, which comprises an aqueous solution of at least one protonic acid and/or an aqueous solution of at least one acid anhydride.
- 19. Composition according to Claim 18, wherein the protonic acid is nitric acid.
- 20. Method for the preparation of a polysiloxane composition, wherein a composition according to any one of Claims 10 to 19 is provided and the silyl alkyl ester is condensed with the reactive silane.
- 21. Method according to Claim 20, wherein the condensation of the silyl alkyl ester with the reactive silane is carried out by heating.
- 22. Method according to Claim 21, wherein the composition is heated for 1 to 24 hours, more preferably for 1 to 10 hours and yet more preferably for 2 to 6 hours at a temperature of 20 to 100°C, more preferably from 40 to





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- 23. Method according to any one of Claims 20 to 22, wherein during the condensation, polysiloxane having a molecular weight and degree of cross-linking is formed, which is dissolved or suspended in the solvent or solvent mixture.
- 24. Method according to any one of Claims 20 to 23, wherein during or after the condensation, a diluting solvent is added.
- 25. Method according to Claim 24, wherein the diluting solvent comprises at least one component selected from methanol, ethanol, 2-propanol, butanol, acetone, propyl acetate, ethyl lactate, propylene glycol propyl ether, diacetone alcohol and methoxypropanol.
- 26. Polysiloxane composition, which is obtainable by a method as defined in any one of Claims 20 to 25.
- 27. Coated substrate, which is obtainable by a method comprising applying the composition as defined in any one of claims 11 to 19 or the polysiloxane composition as defined in claim 26 to the substrate and heating the polysiloxane substrate with the composition or composition applied thereon.
- 28. Coated substrate according to claim 27, wherein applying of said composition or said polysiloxane composition is performed by means of spin techniques.
- 29. Coated substrate according to claim 27 or 28, wherein the substrate is selected from a semiconductor device, a silicon-wafer, a glass plate and a metal plate.
- 30. Use of a composition as defined in any one of Claims 11 to 19 or of a polysiloxane composition as defined in



- 31. Use according to Claim 30, wherein the composition or the polysiloxane composition is applied to the substrate and the substrate with said composition or polysiloxane composition applied thereon is heated.
- 32. Use according to Claim 30 or 31, wherein the composition or the polysiloxane composition is applied to the substrate by means of spin techniques.
- 33. Use according to any one of Claims 30 to 32, wherein the substrate is a semiconductor device or a silicon wafer.
- 34. Method for the photolithographic production of an integrated circuit pattern comprising the steps of:
 - (a) radiating a stack through a mask, said stack comprising the lower substrate, an upper photoresist layer, at least one anti-reflective layer formed from the composition as defined in any one of claims 11 to 19 or from the polysiloxane composition as defined in claim 26, and optionally at least one further layer to be structured, each being located between said substrate and said photoresist layer,
 - (b) developing the exposed stack to produce openings in said photoresist layer,
 - (c) etching a first pattern through said openings in said at least one anti-reflective layer and optionally at least one further layer to be structured, and

- (d) stripping off said photoresist layer, at least one anti-reflective layer and optionally at least one further layer to be structured to produce the integrated circuit pattern.
- 35. Method according to claim 34, wherein the substrate is a semi-conductor device or a silicon wafer.
- 36. Method according to claim 34 or 35, wherein in step (a) the stack is radiated with ultraviolet light having a wavelength of less than 260 nm, particularly 193 nm or 248 nm.
- 37. Method for the preparation of a silyl alkyl ester having the Formula (I)

(I)

in which

 R_1 , R_2 , and R_3 are equal or different and represent alkyl, aryl and heteroaryl,

 R_4 and R_5 are equal or different and represent hydrogen, halogen, alkyl, aryl and heteroaryl, $\;\;$

n is an integer from 1 to 10,

heteroaryl, hydroxy, alkoxy, arylether, substituted and unsubstituted amino group, carboxy group, carboxylic acid ester group, carboxylic acid amide group, sulfonic acid group, sulfonic acid ester group, sulfonic acid ester group, sulfonyl, thio, thioether and nitro,

m is an integer from 0 to 4,

T, X, Y and Z each represent carbon,

a benzo group, which is m-fold substituted with R_6 or which is unsubstituted, is condensed on one of the bonds T-X, X-Y or Y-Z to form a trinuclear aromatic ring system, wherein the silyl alkyl ester group is substituted at the middle ring of said trinuclear aromatic ring system,

wherein a carboxylic acid salt of Formula (II)

(II)

in which k is an integer from 1 to 4 and M is a metal,

is reacted with an organosilicon compound of Formula (III)

$$A \xrightarrow{\begin{array}{c} R_4 \\ I \\ C \\ I \\ R_5 \end{array}} OR_1 OR_2 OR_3$$
 (III)

in which A represents a nucleofugal leaving group.

- 38. Method according to Claim 37, wherein the metal M is selected from the groups Ia, IIa, IIIa, IVa, Ib, IIb, IVb and VIIIb of the periodic table.
- 39. Method according to Claim 37 or 38, wherein k = 1.
- 40. Method according to any one of Claims 37 to 39, wherein M is selected from metals of Group Ia.
- 41. Method according to any one of Claims 37 to 40 wherein the metal M is selected from lithium, sodium and potassium.
- 42. Method according to any one of Claims 37 to 41 wherein the metal M is sodium and/or potassium and particularly potassium.
- 43. Method according to any one of Claims 37 to 42 wherein the nucleofugal leaving group A represents halogen, preferably chlorine and/or bromine and yet more preferably chlorine.
- 44. Method according to any one of Claims 37 to 43 wherein the carboxylic acid salt of Formula (II) is reacted with



the organosilicon compound of Formula (III) in a solvent or solvent mixture, from which the metal salt of the formula MA_K formed is precipitated.

45. Method according to Claim 44, wherein as solvent or solvent mixture, N,N-dimethylformamide and/or N,N-dimethylacetamide is used.